


<b>Search Notes</b> 	<b>Application/Control No.</b> 10711111	<b>Applicant(s)/Patent Under Reexamination</b> HEITLAUF, VIVIENNE M.
	<b>Examiner</b> Choi, Jacob Y	<b>Art Unit</b> 2885

<b>SEARCHED</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
362	103, 249, 806, 808, 396, 122, 124, 396	9/18/2006	JC

<b>SEARCH NOTES</b>		
<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
Class/Subclass (e.g., including class 24, 428, 446) & Text Search Conducted by Examiner	9/18/2006	JC
Updated Search Conducted by Examiner	2/6/2007	JC

<b>INTERFERENCE SEARCH</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>